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SUMMING for formal SBIPTO	Application Number	10/645,924		
INFORMATION DISCLOSURE	Application Number 10/645,924  Filing Date August 22, 2003  Y APPLICANT First Named Inventor Xicheng Jiang	August 22, 2003		
STATEMENT BY APPLICANT	First Named Inventor	Xicheng Jiang		
(Use as many sheets as necessary)'	Art Unit	2819		
and the second s	Examiner Name	To Be Assigned		
Sheet 1 of 1	Attorney Docket Number	1875.3460001/RES/GSB		

		NON PATENT LITERATURE DOCUMENTS	-			
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published				
PID		SINGER, L. et al., "A 12b 65MSample/s CMOS ADC with 82dB SFDR at 120 Mhz", ISSCC 2000, Session 2. Nyquist-Rate Data Converters, Paper MP 2.3, pp. 38-39, IEEE.				
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PIP		CHOI, M. et al., "A 6b 1.3GSample/s A/D Converter in 0.35µm CMOS", ISSCC 2001, Session 8, Nyquist ADCs", Paper 8.1, pp. 126-127, IEEE.				
PIP		SCHOLTENS, P. *A 6b 1.6GSample/s Flash ADC in 0.18µm CMOS using Averaging Termination*, ISSCC 2002, Session 10, High-Speed ADCs, Paper 10.2, pp. 68-69, IEEE.				
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				ATTY. DOCKET NO.	ΙΔ	PPLICATION NO	Page 1 of 1
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	AP1						Yes No
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